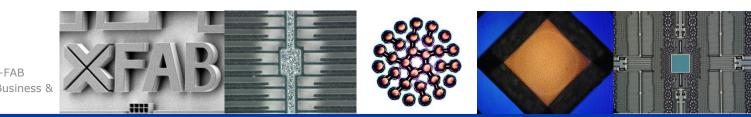
32. Chemnitzer Seminar *»MEMS Technologies and Applications«*

21.-22. Mai 2019, Chemnitz



From sampling to ramping:

Technology and Business Model Challenges for a MEMS Foundry to Address WLP Applications

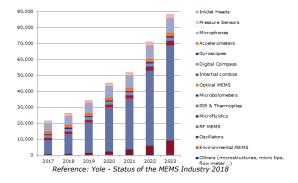


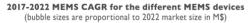
Volker Herbig VP BU MEMS – X-FAB Stefan Ernst Group Manager Business & Strategy

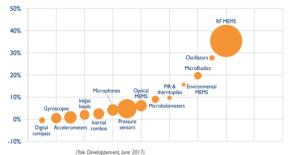
Kontext



- Yole 2017 "The MEMS and Sensor market is growing and new applications are arriving. However, MEMS companies and MEMS foundries are struggling to grow"
- "Everything looks good so where is the problem"
- Voice from trenches: "MEMS high volume manufacturing is super complex"

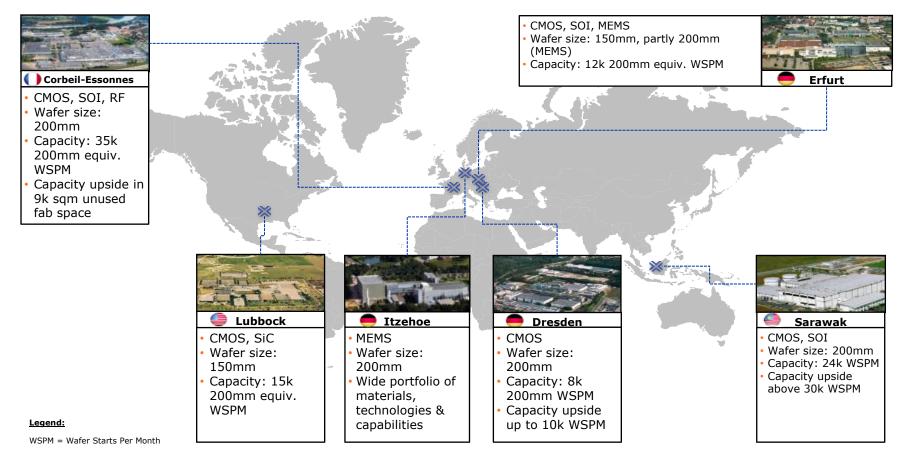






About X-FAB





X-FAB MEMS Foundry

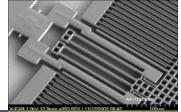


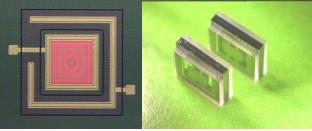
Overview

- High-volume MEMS production operation embedded in CMOS environment
- > 200 mm & 150 mm MEMS operations in 4 clean rooms
- Wide range of processes and materials CMOS and non-CMOS compatible
- > MEMS & CMOS integration
- > Automotive quality system

Application examples

- > Automotive
 - Pressure sensors, Inertial sensors
- Medical / µFludic
 - DNA sequencing, Drug & allergy screening
- Mobile Communication
 - Microphones
- Industrial
 - Gas Sensor

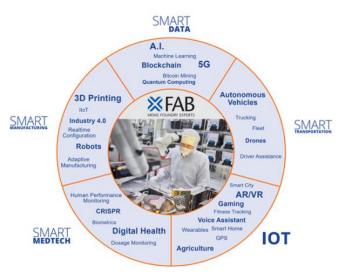




XFAB

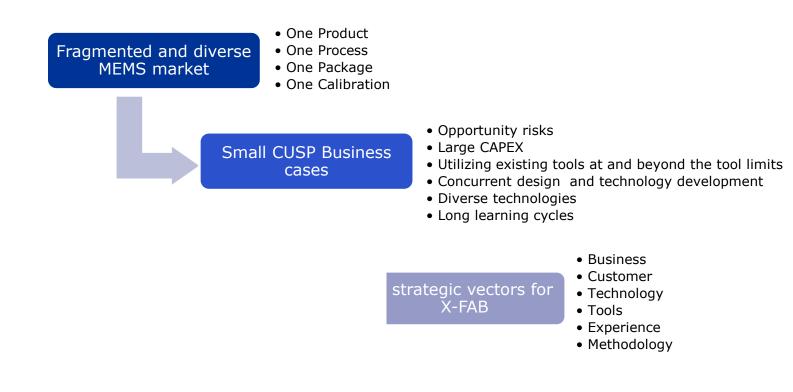
Business Profile

- > 90% of MEMS projects at X-FAB are addressing customer specific technology solutions
 - Typically 3-5 RFQ's per month from all regions
 - 30+ ongoing development programs
 - Concurrent dev't of process and product
 - 30%+ of all programs don't succeed in getting to SOP
- > 10% of new MEMS projects are using X-FAB MEMS open platform technologies
 - Readily qualified technologies,
 - DR, Specs, PDKs
 - Pressure Sensor
 - Inertial Sensor



MEMS Foundry Challenge





Customer



- Foundry vs. customer selection
 - Business case
 - Markets and applications fit
 - Volume, GM, CAPEX
 - Regional fit
 - Experience, expectations, time to market, sampling requirements, NRE
 - Customer relationships
- > Engineering resources
 - Development in mfg. environment vs. development in research lab
 - Resource limitation there was, there is and never will be free engineering bandwidth
 - Design to cost vs. cost of design depending on market and application
- Process complexity
 - Portfolio balancing: e.g. 1 layer vs. 3 wafer stack with 18 layers (MEMS w/o CMOS)

Methodology



- No differences compared with CMOS development methodology
 - FMEA's, PCM concept, patent research, early phase reliability investigations,
 - Alignment with customer on development methodology
 - Frozen process spec vs. fluid spec due to concurrent process and device development
 - Sample production in non-frozen process
- Program management
 - Management of CMOS / MEMS interface
 - Supply chain optimization & management
- Problem solving methodology
 - Fishbone, 8D, 5Why, specific FA
 - Lessons learned

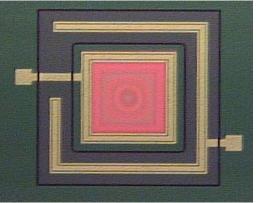
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Technology

> Concurrent tool, process, design and packaging developments

- Long development cycles
- Learning cycles through supply chains are very long
- > Technical differences MEMS vs. CMOS
 - MEMS control philosophy
 - CMOS equipment used for MEMS processing
 - Additional parameter control needed such as mechanical stress, topology
 - Tool operations at critical conditions very thick process layer
 - High requirements on tolerance and homogeneities (typical tolerances for layer thickness 3%-5% MEMS vs. 10% CMOS [analog]





CMOS + MEMS @ X-FAB



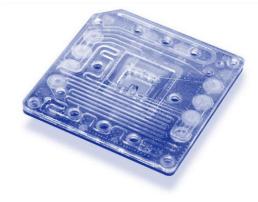
- > CMOS-MEMS integration is an area of focus for X-FAB.
 - realization of very complex technologies and advanced customer products allow different ion and customer retention
- > Opportunity to capture more value in supply chain for foundry
 - MEMS silicon value in value in final product is less compared with IC business
- Required technologies
 - Wafer bonding
 - Capping sensitive sensor and actuator structures
 - Manufacturing worthy integration concept, up to the assembly and packaging of the final device required
 - Through Silicon Vias
 - Manufacturing worthy integration concept, up to the assembly and packaging of the final device, required

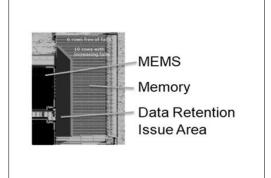
CMOS + MEMS WLP technology challenges

- Mechanical, electrical, chemical, physical properties have to be matched with CMOS, MEMS, Package and calibration requirements
- > Fully holistic view required from project start onwards

Examples

- 1. TSV: wafer bow compensation
- 2. TSV: cross contamination concerns with open passivation
- NVM Data retention issues caused by release etch 100% hermitic seal requited
- 4. Anodic Bond for TGV: glass electrode wafer
- 5. Flat passivation for bond surface preparing
- 6. Fluidic optimization of polymer bond system







WLP technology use @ X-FAB



WLP	Production	Development	Comment
Anodic bonding	Pressure Sensor	Inertial Sensor µFludic	High volume
Glass frit bonding	Inertial Sensor, Optical Sensor		
AlGe		Optical Sensor	
Polymer Bond	µFludics		
Fusion Bond	Pressure Sensor Inertial Sensor		High volume
TSV		Optical Senor µFluidic	

X-FAB WLP Definition & Vision

Vision

> Enable wafer level (sensor) integration and packaging up to direct mounting on PCB

Carrier wafer 400µm thick Si or glass System wafer 200µm thick Insulation (oxide) Optional µT printed elements Active structure CMOS MEMS... Active structure CMOS MEMS... UBM Bump / balls

- > Overall thickness 0.6mm even less is possible
- > AlGe or Glass ftit Bonding with hermetic sealing
- > Grinding of system wafer after bonding no thin wafer handling needed
- X-FAB TSV process

Dicing as last step

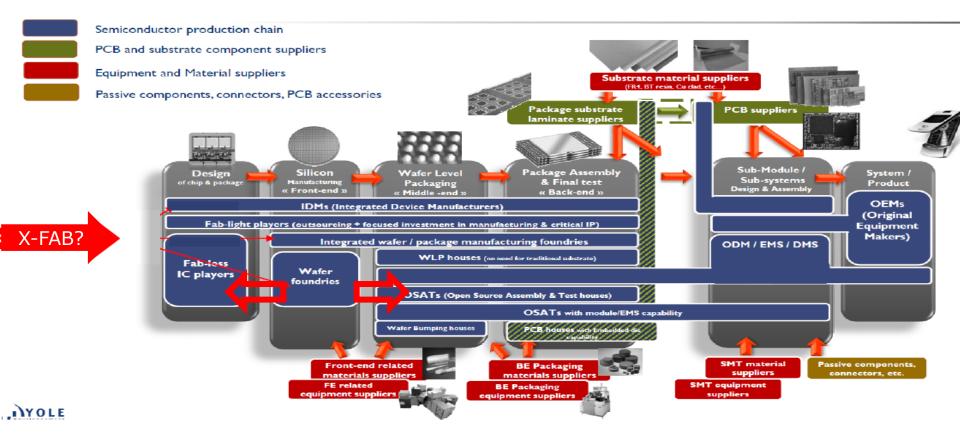
- > Device sidewall passivation (Oxide Cu Polyimide) for all around protection of active structures
- Dicing only through the carrier wafer at end of process





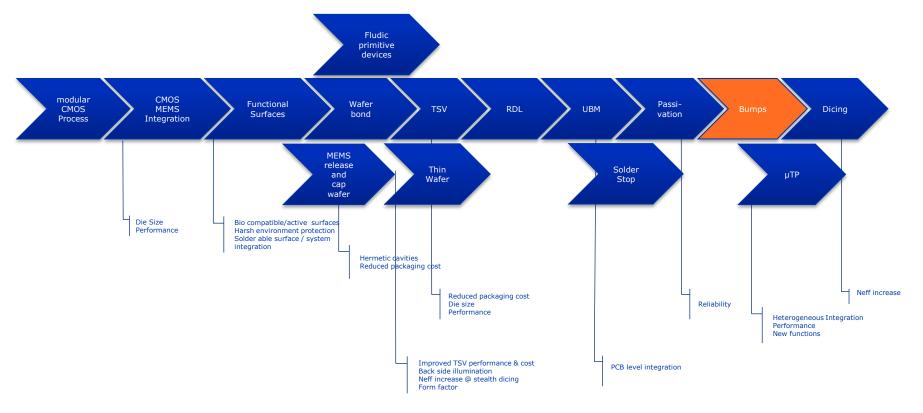
Semiconductor Supply Chain 2020 (Yole view)





WLP Modular Process Concept





Trade Off's

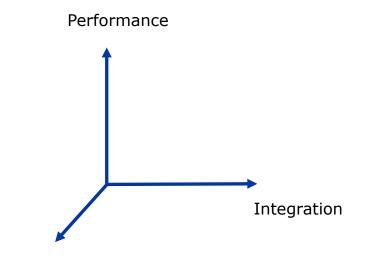
Performance

- Hermitic seal, yield, Bond Strength, Drift, reliability
- Process Integration
 - Wafer bow, release etch, open passivation, pad quality, NVM integration, temperature budget, out gassing, alignment tolerances, wafer thickness, bond frames, noble metal

Cost

- Process complexity
- Capex
 - Tools
 - Metrology, Monitoring
 - Cross contamination
- Opex





Cost

Reuse



- Leverage of high volume mfg. experience:
 - Bond pad protection schemes in MEMS processing
 - Dicing over pads
 - Outgassing in cavities
 - Front side protection vs. edge grip handling capabilities
 -
- > Requirements:
 - Standard Process Blocks and process module reuse
 - Gap development vs. full flow development

	licon Wet Etching	MEMS FOUNDRY EXP		
Process Module				
Description		Key Features		
Characteristics and Function	nal Elements	Application Concrete		
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Cross Contamination

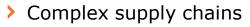


- Leverage of CMOS high volume manufacturing infrastructure requires managing the risks involved
 - Objective is zero risk for CMOS WIP
- > Methodology requirements
 - Developing and sustaining of specific mindset
 - Controlled material flow and related logistics
 - Additional in line tests MEMS and CMOS specific (detailed GOX monitoring)
- Tools and infrastructure
 - Separation by clean room, main frame or chamber required
 - Dedicated tools and handling systems (supported by tool automation)

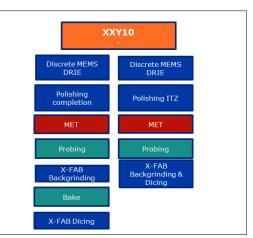


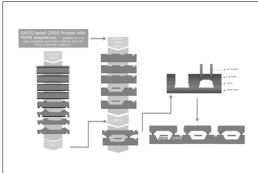
WLP Supply Chain





- Up to three internal fabs and external processing / or probing
- Issues to manage
 - SOP prior process freeze
 - Quality gates are cost drivers (AVI)
 - ERP system
 - Lead time
 - Yield management
 - Foreign material handling
 - Loading swings by consumer business





Key Messages



- We do not expect MEMS WLP high volume manufacturing to become a commodity in the next years
- > We believe managing the business model risk (large capex, small projects) is key
- > We see specs for tools and process constantly being pushed to the limits and above
- > We experience complex supply chain issues
- > We recognize standardization and process module re-use is key



THE MORE THAN MOORE FOUNDRY. Thank you for your attention.